Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/626,068	WEIER ET AL.	
Examiner	Art Unit	
Robert D. Harlan	1713	

SEARCHED					
Class	Subclass	Date	Examiner		
524	523	12/16/2005	RH		
524	555	12/16/2005	RH		
524	560	12/16/2005	RH		
524	562	12/16/2005	RH		
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INTERFERENCE SEARCHED			CE SEARCHED		
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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